

GigaDevice Semiconductor Inc.

**GD32E103&GD32C103 Hardware
Development Guide**

Application Note

AN061

Revision 1.3

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1. Introduction

This article is specially provided for developers of 32-bit general-purpose MCU GD32E103/ GD32C103 series based on ARM® Cortex®-M4 architecture. It provides an overall introduction to the hardware development of GD32E103/ GD32C103 series products, such as power supply, reset, clock, boot mode settings and download debugging. The purpose of this application note is to allow developers to quickly get started and use GD32E103/ GD32C103 series products, and quickly develop and use product hardware, save the time of studying manuals, and speed up product development progress.

This application note guide is divided into seven parts to describe:

1. Power supply, mainly introduces the design of GD32E103/GD32C103 series power management, power supply and reset functions.
2. Clock, mainly introduces the functional design of GD32E103/GD32C103 series high and low speed clocks.
3. Boot configuration, mainly introduces the BOOT configuration and design of GD32E103/GD32C103 series.
4. Typical peripheral modules, mainly introduces the hardware design of the main functional modules of the GD32E103/GD32C103 series.
5. Download and debug circuit, mainly introduces the recommended typical download and debug circuit of GD32E103/GD32C103 series.
6. Reference circuit and PCB Layout design, mainly introduces GD32E103/GD32C103 series hardware circuit design and PCB Layout design notes.
7. Package description, mainly introduces the package forms and names included in the GD32E103/GD32C103 series.

This document also satisfies the minimum system hardware resources used in application development based on GD32E103/ GD32C103 series products.

Table 1-1. Applicable Products

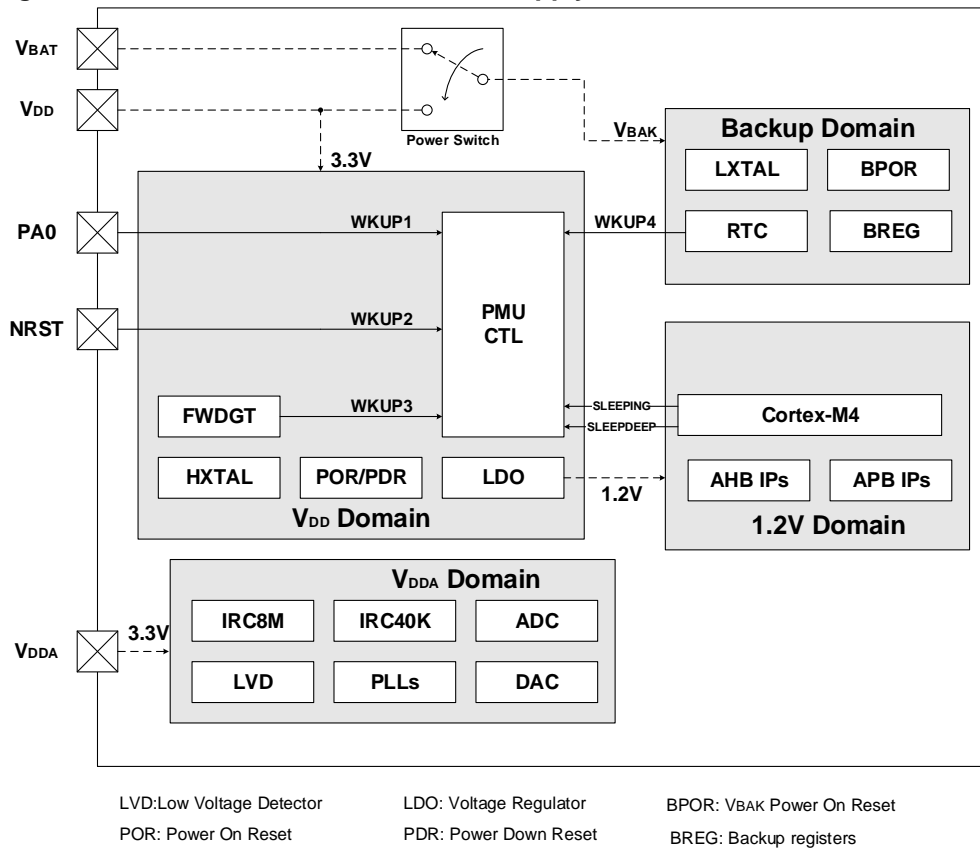
Type	Part Numbers
MCU	GD32E103xx series
	GD32C103xxseries

2. Hardware design

2.1. Power supply

The V_{DD} / V_{DDA} operating voltage range of GD32E103/GD32C103 series products is 1.71 V ~ 3.6 V. For GD32E103/GD32C103 series, there are three power domains, including V_{DD} / V_{DDA} domain, 1.2V domain, and Backup domain, as is shown in [Figure 2-1. GD32E103/GD32C103 Power supply overview](#). The V_{DD}/V_{DDA} domain is powered directly by the power supply, and an LDO is embedded in the V_{DD}/V_{DDA} domain to power the 1.2 V domain. The backup domain power supply V_{BAK} can be powered by V_{DD} or V_{BAT} through the power switch Power Switch. When the V_{DD} power supply is turned off, the power switch can switch the power supply of the backup domain to the V_{BAT} pin. At this time, the backup domain is powered by the V_{BAT} pin (battery).

Figure 2-1. GD32E103/GD32C103 Power supply overview



2.1.1. Backup domain

The backup domain supply voltage range is 1.71 V ~ 3.6 V. In order to ensure the content of the Backup domain registers and the RTC supply, when V_{DD} supply is shut down, V_{BAT} pin can be connected to an optional standby voltage supplied by a battery or by another source. But when V_{DD} is connected, even if the V_{BAT} pin is powered by an external battery, etc., V_{BAK} is still powered by V_{DD} .

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If no external battery is used in the application, it is recommended to connect V_{BAT} pin externally to V_{DD} pin with a 100nF external ceramic decoupling capacitor.

Note: If the V_{BAT} pin is left floating, the Power Switch will switch V_{BAK} to V_{DD} after the MCU is powered on, and the internal V_{DD} will directly supply power to the Backup domain.

2.1.2. V_{DD}/V_{DDA} Power domain

V_{DD}/V_{DDA} power domain supplies power to all areas except the backup domain. If V_{DDA} is not equal to V_{DD} , the voltage difference between the two is required to be no more than 300mV (the internal V_{DDA} and V_{DD} are connected by back-to-back diodes). To avoid noise, V_{DDA} can be connected to V_{DD} through an external filter circuit, and the corresponding V_{SSA} is connected to V_{SS} through a specific circuit (single-point grounding, through 0Ω resistors or magnetic beads, etc.).

In order to improve the conversion accuracy of the ADC, the independent power supply for V_{DDA} can make the analog circuit achieve better characteristics. There is a V_{REF} pin ($1.8V \leq V_{REFP} \leq V_{DDA}$, $V_{REFN} = V_{SSA}$) for ADC independent power supply on the large package.

- 100 and more pin package chips contain V_{REFP} and V_{REFN} , V_{REFP} can use an external reference power supply, or can be directly connected to V_{DDA} , V_{REFN} must be connected to V_{SSA} .
- 64 and less pin package chips do not have V_{REFP} and V_{REFN} , they are directly connected to V_{DDA} and V_{SSA} internally, and all analog modules are powered by V_{DDA} (including ADC/DAC).

2.1.3. Power supply design

The system needs a stable power supply. There are some important things to pay attention to when developing and using:

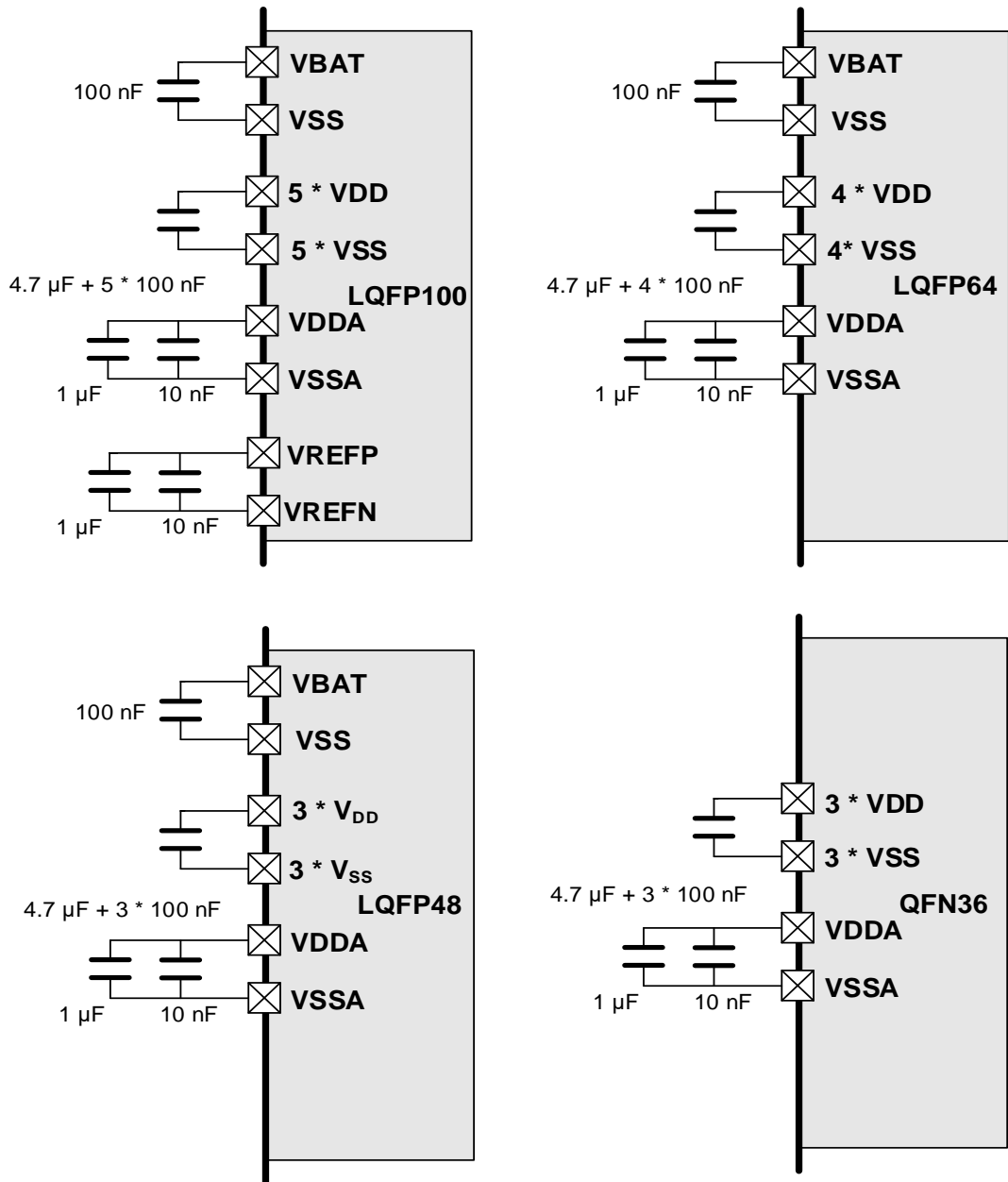
- V_{DD} pin must be connected to an external capacitor (N*100nF ceramic capacitor + not less than 4.7uF tantalum capacitor, at least one V_{DD} needs to be connected to GND with a capacitor of not less than 4.7uF, and other V_{DD} pins are connected to 100nF).
- V_{DDA} pin must be connected with an external capacitor (10nF+1uF ceramic capacitor is recommended).
- V_{BAT} pin must be connected to an external battery (1.71V ~ 3.6V). If there is no external battery, it is recommended to connect the V_{BAT} pin to the ground through a 100nF capacitor and then connect it to the V_{DD} pin
- V_{REFP} pin can be directly connected to V_{DDA} . If a separate external reference voltage is used on V_{REF} ($1.8V \leq V_{REFP} \leq V_{DDA}$, $V_{REFN} = V_{SSA}$), a 10nF+1uF ceramic capacitor must also be connected to ground on the V_{REFP} pin.
- Even though all V_{DD} 's are connected internally and all V_{SS} are connected internally, all V_{DD} 's must be connected together and all V_{SS} must be connected together outside the chip.
- V_{DDA} partially supplies power to all analog circuits, including ADC module, reset circuit,

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PVD(programmable voltage Monitor), PLL, power-on reset (POR) and power-off reset (PDR) modules, switches that control VBAT switching, etc.

- Even if you do not use ADC function, you need to connect to VDDA.
- It is strongly recommended that VDD and VDDA use the same power supply.
- The voltage difference between the VDD and VDDA cannot exceed 300mV. The VDD and VDDA should be powered on or off at the same time.

Figure 2-2. GD32E103/GD32C103 Recommend Power Supply Design



GD32E103/GD32C103

Note:

1. All decoupling capacitors need to be as close as possible to the pins on the PCB board.
2. When the MCU power supply voltage is unstable or there is a risk of voltage drop, it is recommended to adjust the 4.7uF capacitor not less than 10uF.

3. LQFP64, LQFP48, QFN36: VREFP and VDDA are connected internally, VREFN and VSSA are connected internally.

2.2. Power supply detection and reset

This section is based on the GD32E103xx series chips and GD32C103xx series chips of version A, and the default VDD and VDDA pins remain connected, and are powered by the same power supply.

GD32E103/GD32C103 series reset control includes three resets: power reset, system reset and backup domain reset. A power reset is a cold reset, which resets all systems except the backup domain when the power is turned on. During the power and system reset process, NRST will maintain a low level until the reset is over. When the MCU cannot be executed, the NRST pin waveform can be monitored by an oscilloscope to determine whether the chip has been reset.

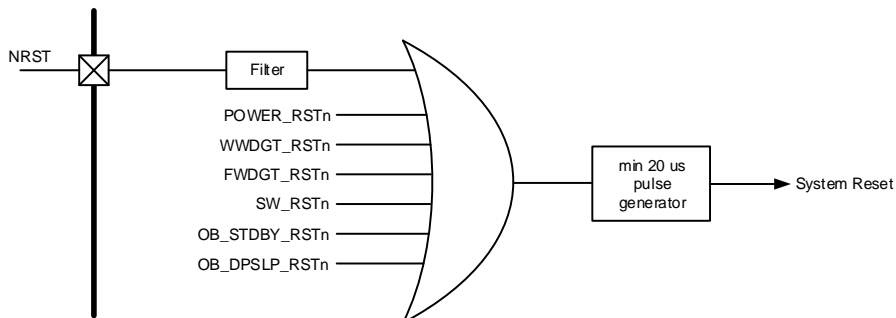
In addition, the MCU reset source can be judged by querying the register RCU_RSTSCK (0x40021024). This register can only clear the flag bit after a power-on reset. Therefore, during use, after the reset source is obtained, the reset flag can be cleared through the RSTFC control bit. When the watchdog is reset or other reset events, it can be more accurately reflected in the RCU_RSTSCK register.

Figure 2-3. RCU_RSTSCK Register

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16
LP RSTF	WWDGT RSTF	FWDGT RSTF	SW RSTF	POR RSTF	EP RSTF	Reserved	RSTFC	Reserved							
r	r	r	r	r	r		rw								
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
Reserved													IRC40K STB	IRC40KE N	

MCU integrates a power-up / power-down reset circuit, when a reset occurs, the system reset pulse generator ensures that each reset source (external or internal) can have a low level pulse delay of at least 20µs.

Figure 2-4. System Reset Circuit

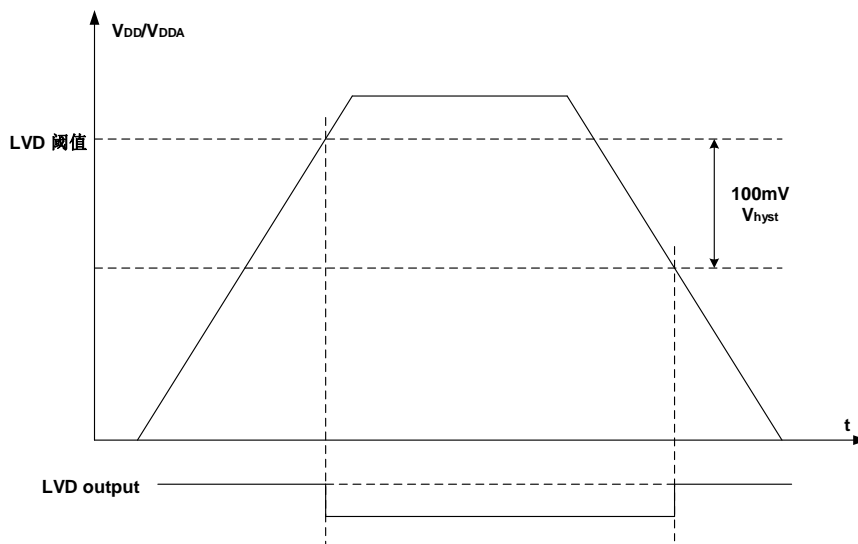


2.2.1. LVD

The function of the LVD is to detect whether the V_{DD}/V_{DDA} supply voltage is lower than the low-voltage detection threshold (2.1 V ~ 3.1 V), which is configured by the LVDT[2:0] bits in the power control register (PMU_CTL). LVD is enabled by LVDEN setting. The LVDF bit in the power status register (PMU_CS) indicates whether a low voltage event occurs. The event is connected to the 16th line of EXTI. The user can configure the 16th line of EXTI to generate a corresponding interrupt. (LVD interrupt signal depends on the rising or falling edge configuration of EXTI line 16). The value of the hysteresis voltage V_{hyst} is 100mV.

LVD application: When the MCU power supply is subject to external interference, such as a voltage drop, we can set the low voltage detection threshold (the threshold is greater than the PDR value) through LVD. Once it falls to the threshold, the LVD interrupt is turned on, which can be used in the interrupt function. Set operations such as soft reset to avoid other exceptions from the MCU.

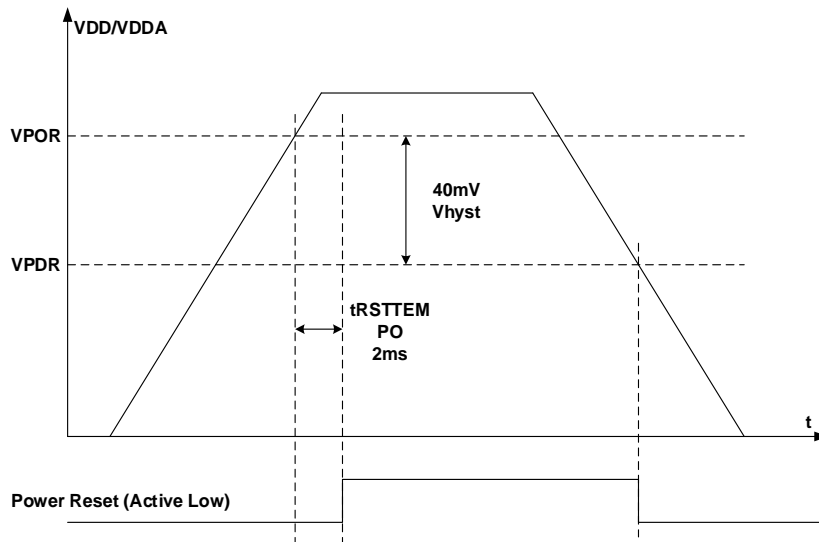
Figure 2-5. LVD Threshold Waveform



2.2.2. POR / PDR

The chip integrates a POR/PDR (power-on/power-down reset) circuit to detect V_{DD}/V_{DDA} and generate a power reset signal to reset the entire chip except the backup domain when the voltage is lower than a certain threshold. V_{POR} represents the threshold voltage of power-on reset, the typical value is about 1.66, V_{PDR} represents the threshold voltage of power-down reset, and the typical value is about 1.62V. The value of the hysteresis voltage V_{hyst} is about 40mV.

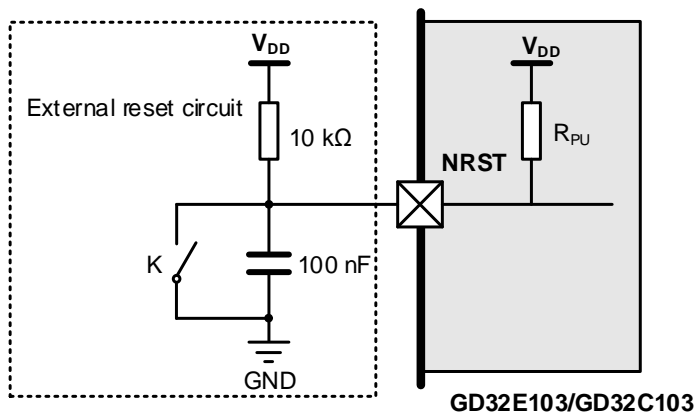
Figure 2-6. Power-on/Power-down Reset Waveforms



2.2.3. NRST Pin

To prevent a false trigger reset, the NRST pin is recommended to place a capacitor (typically 100nF).

Figure 2-7. Recommend External Reset Circuit



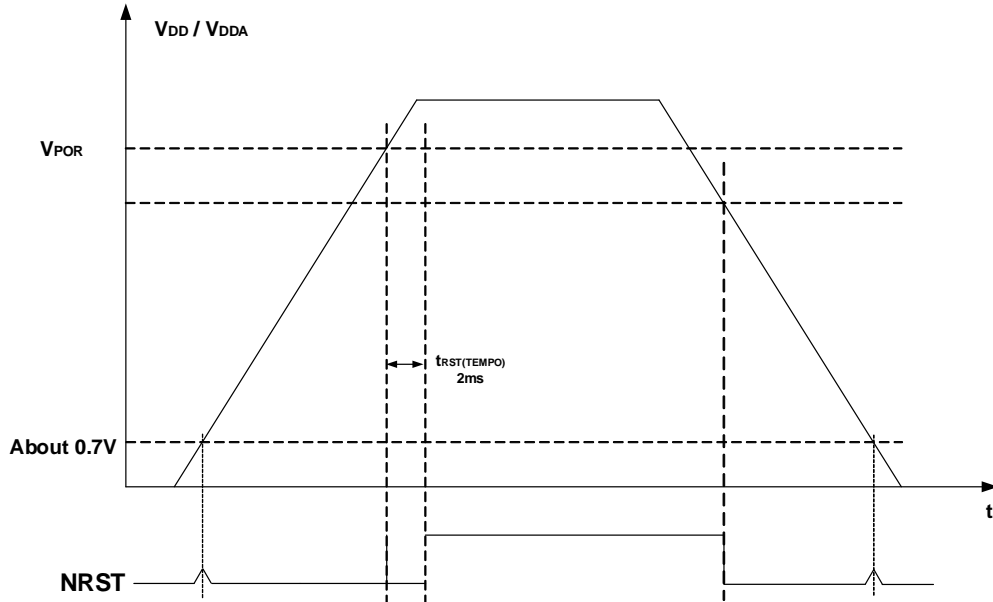
Note:

1. The pull-up resistor is recommended to be 10kΩ, so that voltage interference will not cause the chip to work abnormally.
2. If the influence of static electricity is considered, an ESD protection diode can be placed at the NRST pin.
3. Although there is a hardware POR circuit inside the MCU, it is still recommended to add an external NRST reset resistor-capacitor circuit.
4. If the MCU starts abnormally (due to voltage fluctuations, etc.), the capacitance value of NRST to ground can be appropriately increased, and the MCU reset completion time can be extended to avoid the abnormal power-on sequence area.

Due to the threshold voltage characteristics of the MOS tube, when VDD/VDDA < 0.7V during

the chip power-on and power-off process, pulling down the MOS tube inside the chip will not pull down the NRST pin. That is, when $V_{DD}/V_{DDA} \approx 0.7V$ is used during the chip power-on and power-off process, a tiny pulse will occur, which does not affect the normal operation of the chip, as shown in [Figure 2-8. NRST pin power-on and power-off MOS tube pulse diagram](#).

Figure 2-8. NRST pin power-on and power-off MOS tube pulse diagram



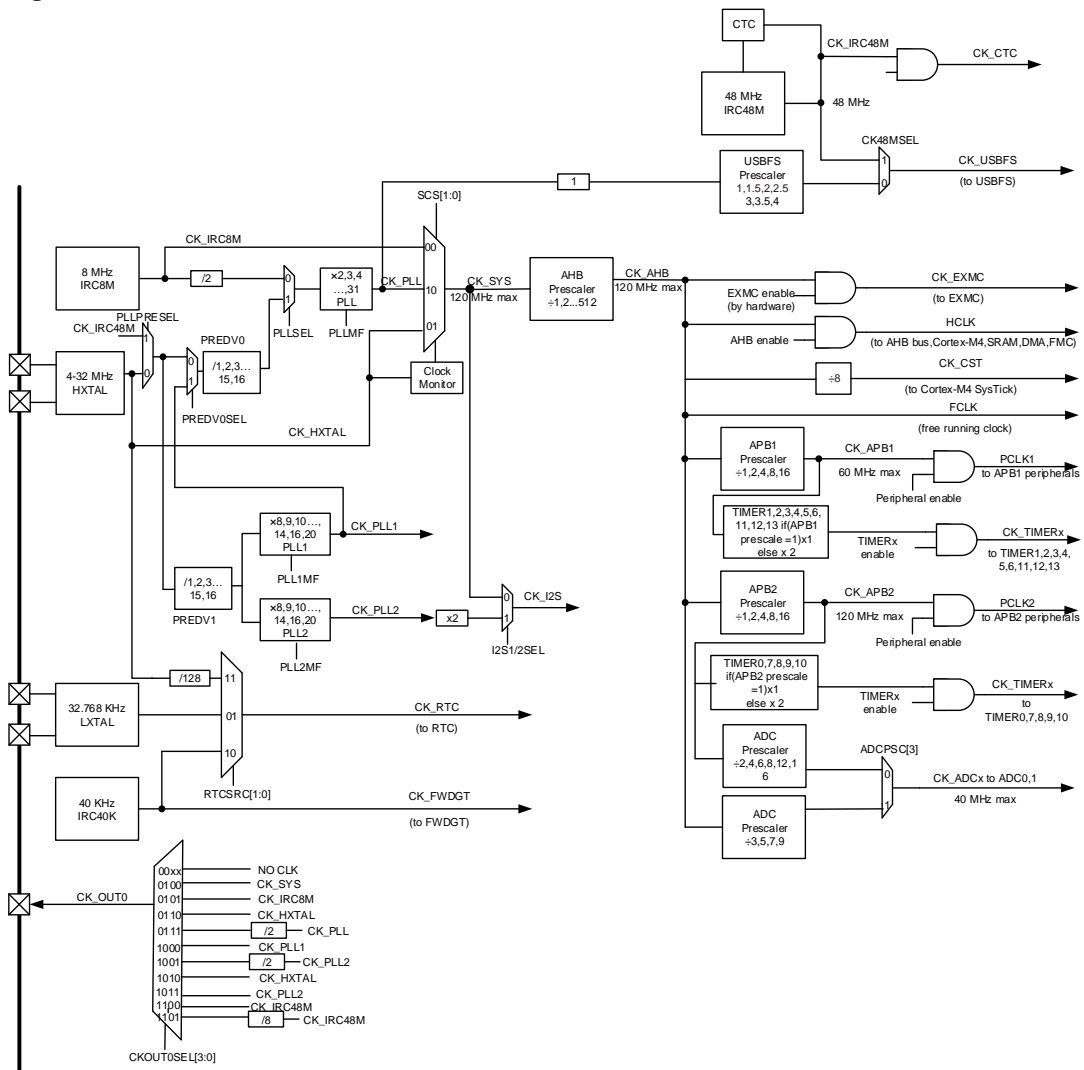
Due to the difference in charging and discharging speed, the pulse duration of the falling edge is longer than that of the rising edge, and the duration of both is ms class.

2.3. Clock

GD32E103/GD32C103 series has a complete clock system inside. You can choose the appropriate clock source according to different applications. The main features of the clock are:

- 4-32 MHz external high-speed crystal oscillator (HXTAL)
- 8 MHz internal high-speed RC oscillator (IRC8M)
- 48 MHz internal high-speed RC oscillator (IRC48M)
- 32.768 kHz external low-speed crystal oscillator (LXTAL)
- 40 kHz internal low speed RC oscillator (IRC40K)
- PLL clock source can be selected from HXTAL, IRC8M or IRC48M
- HXTAL clock can be monitored

Figure 2-9. GD32E103&GD32C103 Clock Tree



2.3.1. External high-speed crystal oscillator clock (HXTAL)

4-32MHz external high-speed crystal oscillator (passive crystal) can provide accurate master clock for the system. The crystal for that specific frequency must be placed close to the HXTAL pin, and the external resistors and matching capacitors connected to the crystal must be adjusted according to the chosen oscillator parameters. HXTAL can also use the bypass input mode to input the clock source (1-50MHz active crystal oscillator, etc.). When the bypass input is used, the signal is connected to OSC_IN, and OSC_OUT remains floating. The Bypass function of HXTAL needs to be turned on in software (enable the HXTALBPS bit in RCU_CTL).

Figure 2-10. HXTAL External Crystal Circuit

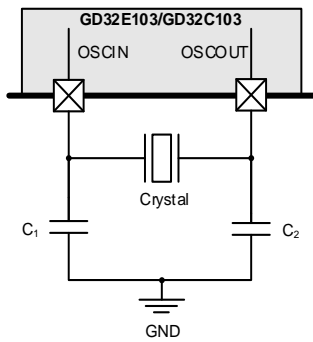
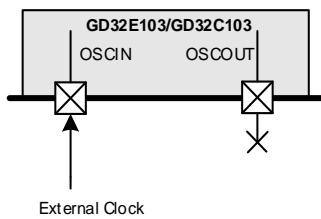


Figure 2-11. HXTAL External Clock Circuit



Note:

1. When using the bypass input, the signal is input from OSC_IN, and OSC_OUT remains floating.
2. For the size of the external matching capacitor, please refer to the formula: $C_1 = C_2 = 2 * (C_{LOAD} - C_S)$, where C_S is the stray capacitance of the PCB and MCU pins, with a typical value of 10pF. When it is recommended to use an external high-speed crystal, try to choose a crystal load capacitance of about 20pF, so that the external matching capacitors C_1 and C_2 can be 20pF, and the PCB layout should be as close as possible to the crystal pin.
3. C_S is the parasitic capacitance on the PCB board traces and IC pins. The closer the crystal is to the MCU, the smaller the C_S , and vice versa. Therefore, in practical applications, when the crystal is far away from the MCU and causes the crystal to work abnormally, the external matching capacitor can be appropriately reduced.
4. When using an external high-speed crystal, it is recommended to connect a 1MΩ resistor in parallel at both ends of the crystal to make the crystal easier to vibrate.
5. Accuracy: external active crystal > external passive crystal > internal IRC8M.
6. When the active crystal oscillator is used normally, Bypass will be turned on. At this time, the high level is required to be no less than 0.7 V_{DD} , and the low level is no more than 0.3 V_{DD} .

2.3.2. External low-speed crystal oscillator clock (LXTAL)

The LXTAL is an external low speed crystal or ceramic resonator with a frequency of 32.768 kHz. It provides a low power consumption and high precision clock source for real-time clock circuit. The LXTAL oscillator can be started and turned off by setting the LXTALEN bit in the

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backup domain control register (RCU_BDCTL). The LXTALSTB bit in the backup domain control register RCU_BDCTL is used to indicate whether the LXTAL clock is stable. If the corresponding interrupt enable bit LXTALSTBIE in the interrupt register RCU_INT is set to '1', an interrupt will be generated after LXTAL stabilizes.

The LXTALBPS and LXTALEN positions' 1' of the domain control register RCU_BDCTL can be backed up to select external clock bypass mode. CK_LXTAL is consistent with the external clock signal connected to OSC32IN pins.

Figure 2-12. LXTAL External Crystal Circuit

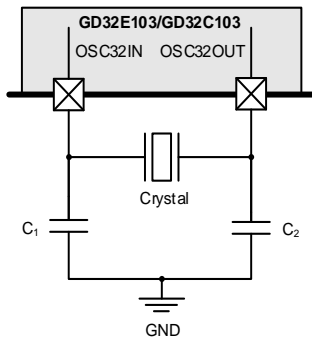
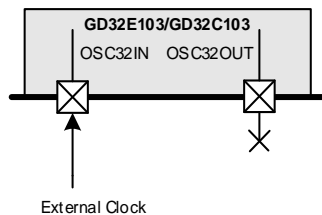


Figure 2-13. LXTAL External Clock Circuit



Note:

1. When using the bypass input, the signal is input from OSC32_IN, and OSC32_OUT remains floating.
2. For the size of the external matching capacitor, please refer to the formula: $C_1 = C_2 = 2 * (C_{LOAD} - C_S)$, where C_S is the stray capacitance of the PCB and MCU pins, the empirical value is between 2pF-7pF, and 5pF is recommended as a reference value calculation. When it is recommended to use an external crystal, try to choose a crystal load capacitance of about 10pF, so that the externally connected matching capacitors C_1 and C_2 can be 10pF, and the PCB layout should be as close to the crystal pin as possible.
3. When the RTC selects IRC40K as the clock source and uses the VBAT external independent power supply, if the MCU is powered off at this time, the RTC will stop counting. After the power is re-energized, the RTC will continue to accumulate the counting value according to the previous count value. If the application needs to use VBAT to power the RTC, the RTC can still time normally, and the RTC must select LXTAL as the clock source.

2.3.3. Clock output capability (CKOUT)

For GD32E103/GD32C103 series MCU, you can select different clock signal output by configuring the CKOUT0SEL[3:0] bits of the clock register RCU_CFG0, and the corresponding GPIO pin PA8 needs to be configured as a multiplexing function to output the selected signal.

Table 2-1. CKOUT0SEL[3:0] Control Bits

CKOUT0SEL[3:0]	Clock Source
00xx	NA
0100	CK_SYS
0101	CK_IRC8M
0110	CK_HXTAL
0111	CK_PLL/2
1000	CK_PLL1
1001	CK_PLL2/2
1010	CK_HXTAL
1011	CK_PLL2

2.3.4. HXTAL Clock monitor (CKM)

Set the HXTAL clock monitoring enable bit CKMEN in the clock control register RCU_CTL, HXTAL can enable the clock monitoring function. This function must be enabled after HXTAL start-up delay and disabled after HXTAL is stopped. Once an HXTAL failure is detected, the HXTAL will be automatically disabled, The HXTAL clock blocking interrupt flag bit CKMIF in interrupt register RCU_INT will be set to '1', generating an HXTAL failure event, and the HXTAL fault event is generated. The interrupt caused by this fault is connected to the non-maskable interrupt NMI of the Cortex-M4. If HXTAL is selected as the clock source for the system, PLL, or RTC, the HXTAL failure will cause IRC8M to be selected as the system clock source, PLL will be automatically disabled, and the RTC clock source needs to be reconfigured.

Note: If HXTAL is selected as the system clock, PLL or RTC clock source, HXTAL failure will prompt the selection of IRC8M as the system clock source, the PLL will be automatically disabled, and the RTC clock source needs to be reconfigured.

2.4. Startup Configuration

GD32E103/GD32C103 series provides three boot modes, which can be selected by the BOOT0 bit and the BOOT1 pin to determine the boot option. When designing the circuit, run the user program, the BOOT0 pin cannot be left floating, it is recommended to connect a 10kΩ resistor to GND; when running the System Memory to update the program, you need to connect the BOOT0 pin to high and the BOOT1 pin to low. After the update is completed, the user program can be run after the BOOT0 is connected to a low level; the SRAM execution

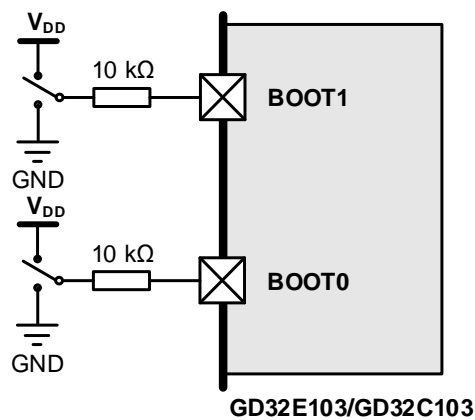
program is mostly used in the debugging status.

The embedded Bootloader is stored in the system storage space for reprogramming the FLASH memory. In GD32E103/GD32C103 devices, the Bootloader can interact with the outside world through USART0 (PA9 and PA10).

Table 2-2. Bootloader Mode

BOOT Mode	BOOT1	BOOT0
Main Flash Memory	X	0
System Memory	0	1
On Chip SRAM	1	1

Figure 2-14. Recommend BOOT Circuit Design



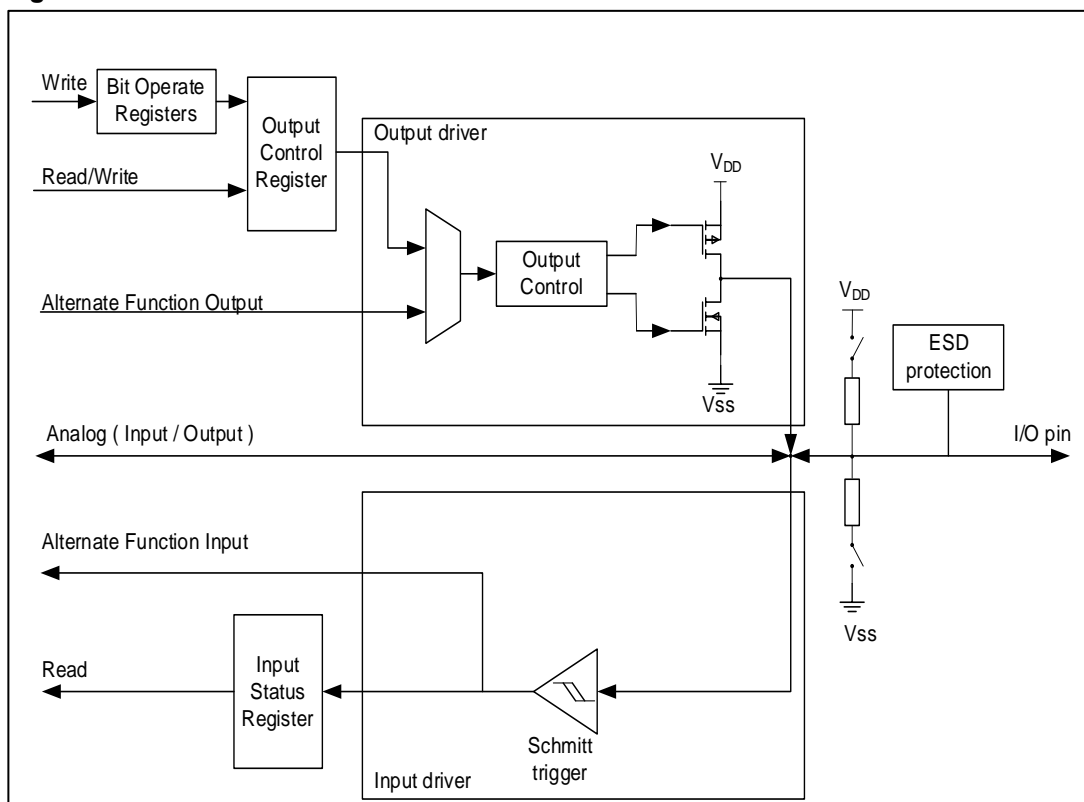
Note:

1. After the MCU is running, if the BOOT status is changed, it will take effect after the system is reset.
2. Once the BOOT1 pin state is sampled, it can be released for other purposes.

2.5. Typical Peripheral Modules

2.5.1. GPIO Circuit

The GPIO interface includes 5 groups of general-purpose input/output ports, each group of ports provides up to 16 general-purpose input/output pins, which are PA0 ~ PA15, PB0 ~ PB15, PC0 ~ PC15, PD0 ~ PD15 and PE0 ~ PE15, each pin can be independently configured through registers, the basic structure of GPIO port is shown in the following figure.

Figure 2-15. Basic Structure of Standard IO

Note:

1. The IO port is divided into 5V tolerance and non-5V tolerance. When using, pay attention to distinguish the voltage tolerance of the IO port, see Datasheet for details.
2. When the 5V-tolerant IO port is directly connected to 5V, it is recommended that the IO port be configured in open-drain mode and externally pull up to work.
3. After the IO port is powered on and reset, the default mode is floating input, and the level characteristics are uncertain. In order to obtain more consistent power consumption, it is recommended that all IO ports be configured as analog inputs and then modified to the corresponding mode according to application requirements (chip Ports that are not exported internally also need to be configured).
4. To improve EMC performance, it is recommended to pull up or pull down the unused IO pins by hardware.
5. The drive capability of the three IO ports PC13, PC14, and PC15 is weak, and the output current capability is limited (about 3mA). When configured in output mode, the operating speed cannot exceed 2MHz (the maximum load is 30pF).
6. The same label PIN in multiple groups can only configure one port as an external interrupt. For example, PA0, PB0, and PC0 only support one of the three IO ports to generate external interrupts, and do not support three external interrupt modes.
7. IO driving LED, it is recommended to consider the use of irrigation current as far as possible.

2.5.2. USART Circuit

Universal Synchronous Asynchronous Receiver Transmitter (USART) provides a flexible and convenient serial data exchange interface, and data frames can be transmitted in full-duplex or half-duplex, synchronous or asynchronous mode. The USART provides a programmable baud rate generator that divides the system clock to generate the specific frequency required for USART transmission and reception.

USART not only supports the standard asynchronous transceiver mode, but also implements some other types of serial data exchange modes, such as infrared coding specification, SIR, smart card protocol, LIN, and synchronous single-duplex mode. It also supports multiprocessor communication and Modem flow control operation (CTS/RTS). Data frames support transmission from the LSB or MSB. Both the polarity of the data bits and the TX/RX pins can be flexibly configured.

USART supports DMA function to realize high-speed data communication.

Table 2-3. USART Important Pin Description

Pin	Type	Description
RX	Input	Receive data
TX	Output I/O (Single-Wire Mode/ Smart Card Mode)	Send data, when USART is enabled, if no data is sent, the default is high level.
CK	Output	Serial clock signal for synchronous communication
nCTS	Input	Hardware flow control mode send enable signal
nRTS	Output	Hardware flow control mode send request signal

2.5.3. ADC Circuit

The GD32E103/GD32C103 series integrates a 12-bit SAR ADC, which has up to 18 channels and can measure 16 external and 2 internal signal sources. The internal signal is the temperature sensor channel (ADC0_CH16) and the internal reference voltage input channel (ADC0_CH17). The temperature sensor reflects the change in temperature and is not suitable for measuring absolute temperature. If accurate temperature measurement is required, an external temperature sensor must be used. The internal reference voltage V_{REFINT} provides a regulated voltage output (1.2V) to the ADC and is internally connected to ADC0_CH17. The supply voltage of the ADC is 2.4V to 3.6V, and the general supply voltage is 3.3V. ADC input range: $V_{REFN} \leq V_{IN} \leq V_{REFP}$.

Table 2-4. ADC Internal signal

Internal signal name	Signal types	Instructions
V_{SENSE}	Input	Internal temperature sensor voltage output
V_{REFINT}	Input	Internal reference voltage output

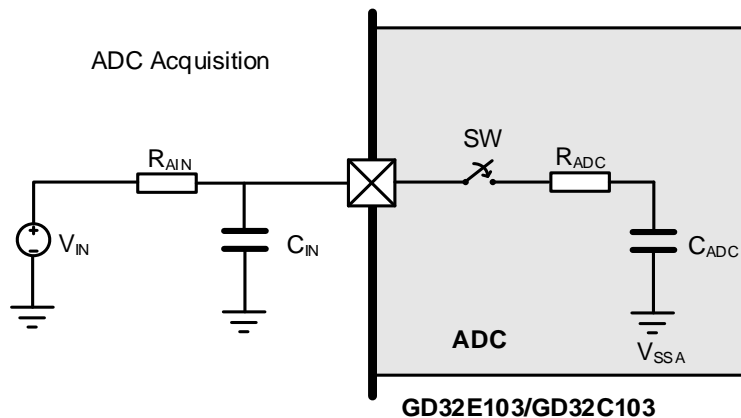
Table 2-5. ADC Pin definition

Name	Signal types	Annotation
V _{DDA}	Input, analog power supply	Analog power input is equal to V _{DD} , 2.4V≤V _{DDA} ≤3.6V
V _{SSA}	Input, analog power supply ground	Analog, is equal to V _{SS}
V _{REFP}	Input, simulating reference voltage	ADC positive reference voltage, 1.8V ≤V _{REFP} ≤V _{DDA}
V _{REFN}	Input, negative analog reference voltage	ADC negative reference voltage, V _{REFN} = V _{SSA}
ADC _X _IN[15:0]	Input, analog signal	Up to 16 external access ways

Note: V_{DDA} and V_{SSA} must be connected to V_{DD} and V_{SS}, respectively.

If the ADC collects the external input voltage in the process of use, if the sampled data fluctuates greatly, it may be due to the interference caused by the fluctuation of the power supply. It can be calibrated through the sampling internal VREFINT to invert the external sampling voltage.

When designing ADC circuit, it is recommended to place a small capacitor at the ADC input pin, and a small capacitor of 500pF is recommended.

Figure 2-16. ADC Acquisition Circuit Design


When $f_{ADC} = 42\text{MHz}$, the relationship between input impedance and sampling period is as follows. In order to obtain better conversion results, it is recommended to reduce the frequency of f_{ADC} as much as possible, and select a larger sampling period as much as possible. In the design of external circuit, input impedance should also be reduced as much as possible.

Table 2-6. $f_{ADC}=42\text{MHz}$ Relationship between Sampling period and External input impedance

T _s (cycles)	t _s (us)	R _{AINmax} (kΩ)
1.5	0.04	0.47
7.5	0.18	3.15
13.5	0.32	5.82
28.5	0.68	12.55

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T_s (cycles)	t_s (μ s)	R_{AINmax} (k Ω)
41.5	0.99	18.35
55.5	1.32	24.55
71.5	1.70	NA
239.5	5.70	NA

The integral linear error (ILE) and differential linear error (DLE) of the ADC module depend on the design of the ADC module, and it is difficult to calibrate them. Doing multiple conversions and averaging reduces their impact. Offset and gain errors can simply be compensated using the self-calibration function of the ADC module. Factors affecting ADC accuracy are as follows.

1. Power supply noise, especially high frequency noise linear regulator of switching power supply (SMPS) has better output. It is strongly recommended to connect the filter capacitor at the output end of the rectifier.
2. If switching power supply is used, it is recommended to use a linear voltage regulator for the analog part of the power supply.
3. It is recommended that a capacitor with high frequency characteristics be connected between the power cable and the ground cable, that is, a capacitor of 0.1 μ F and a capacitor of 1-10 μ F should be placed near the power supply end.
4. A separate decoupling capacitor is required for each pair of V_{DD} and V_{SS} pins.
5. V_{DDA} pins must be connected to 2 external decoupling capacitors (10nF ceramic capacitor +1 μ F tantalum or ceramic capacitor).
6. For 100-pin packages, an external ADC reference input voltage can be connected to V_{REF+} to improve accuracy against low input voltages.
7. Add an external filter to eliminate high-frequency noise.
8. The ground wire is arranged around the analog signal line to produce shielding, which can effectively reduce the crosstalk noise.

2.5.4. DAC Circuit

The digital/analog converter of GD32E103/GD32C103 can convert 12-bit digital data to voltage output on external pins. Data can be in 8-bit or 12-bit mode, left-justified or right-justified. When external triggering is enabled, DMA can be used to update digital data on the input. At the output voltage, the DAC output buffer can be used to obtain higher drive capability. The two DACs can work independently or concurrently.

Table 2-7. DAC Related Pin Description

Name	Description	Signal type
V_{DDA}	Analog power	Input, Analog power
V_{SSA}	Analog power ground	Input, Analog power ground
V_{REFP}	DAC positive reference voltage, $1.8V \leq V_{REFP} \leq V_{DDA}$	reference voltage
DAC_OUTx	DACx analog output	Analog output signal

Before enabling the DAC module, the GPIO port (PA4 corresponds to DAC0, PA5 corresponds to DAC1) should be configured in analog mode.

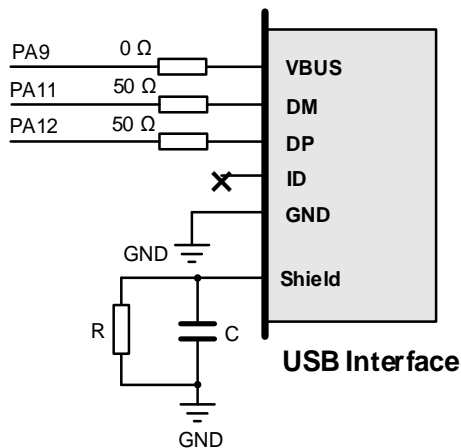
2.5.5. USB Circuit

GD32E103/GD32C103 series MCU has embedded USB interface, which is a USBFS module. The USB protocol requires a clock precision of at least 500ppm, which may not be achieved by an internal clock. Therefore, you are advised to use an external crystal or active crystal oscillator as the USB clock source.

GD32E103/GD32C103 series USB can be designed as BOTH USB device and USB host. When designed as a Device, if PA9 is connected to VBUS, DP line does not need to be connected to 1.5K pull-up resistor externally; If PA9 is not connected to VBUS, if the VBUSIG control bit in the USBFS_GCCFG register has been configured, then the USB_DP data cable can not be connected to an external 1.5K pull-up resistor. If the register is not configured, then the USB_DP data cable needs to be connected to an external 1.5K pull-up resistor.

In order to improve the ESD performance of USB, it is recommended to design a resistance and capacitance discharge isolation circuit for the USB shell.

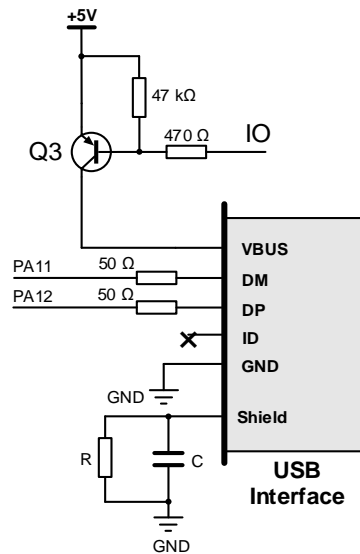
Figure 2-17. Recommend USB-Device Reference Circuit



Recommended: R = 1MΩ, C = 4700 pF.

Note: After configuring the VBUSIG control bit in the USBFS_GCCFG register, the VBUS does not connect to PA9. PA9 can be released for other functions. If the VBUSIG control bit is not configured, PA9 must connect to an external VBUS.

Figure 2-18. Recommend USB-Host Reference Circuit

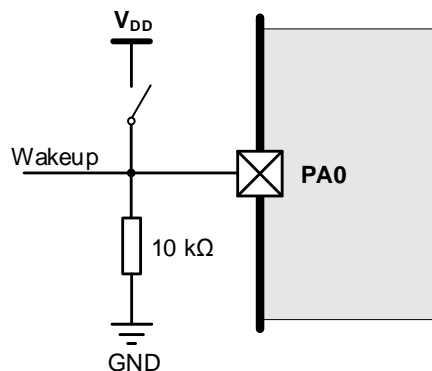


Recommended: R = 1MΩ, C = 4700 pF.

2.5.6. Standby mode wake-up circuit

The GD32E103/GD32C103 series supports three low-power modes, namely sleep mode, deep-sleep mode and standby mode. The standby mode with the lowest power consumption is the standby mode, which requires the longest wake-up time. The WKUP wake pin reference circuit is designed as follows:

Figure 2-19. Recommend Standby External Wake-up Pin Circuit Design



Note: This mode needs to be noted in circuit design, if there is a series resistance between PA0 and VDD, it may increase additional power consumption.

2.6. Download the debug circuit

GD32E103/GD32C103 series cores support JTAG debug interface and SWD interface. The JTAG interface standard is a 20-pin interface, including 5 signal interfaces, and the SWD interface standard is a 5-pin interface, including 2 signal interfaces.

Note: After reset, the debug related ports are in input PU/PD mode, where:

PA15: JTDI is in pull-up mode.

PA14: JTCK/SWCLK in pull-down mode.

PA13: JTMS/SWDIO in pull-up mode.

PB4: NJTRST is in pull-up mode.

PB3: JTDO is floating mode.

Table 2-8. JTAG Download Debug Interface Assignment

Alternate function	GPIO Port
JTMS	PA13
JTCK	PA14
JTDI	PA15
JTDO	PB3
NJTRST	PB4

Figure 2-20. Recommend JTAG Wiring Reference Design

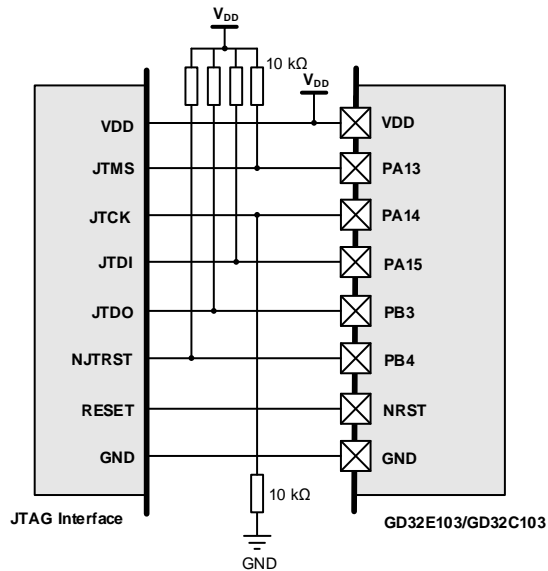
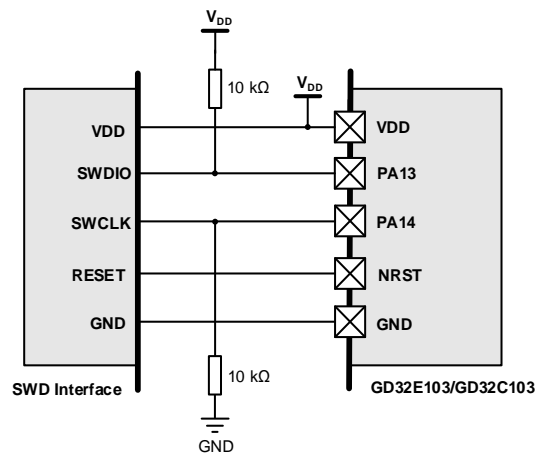


Table 2-9. SWD Download Debug Interface Assignment

Alternate function	GPIO Port
SWDIO	PA13
SWCLK	PA14

Figure 2-21. Recommend SWD Wiring Reference Design

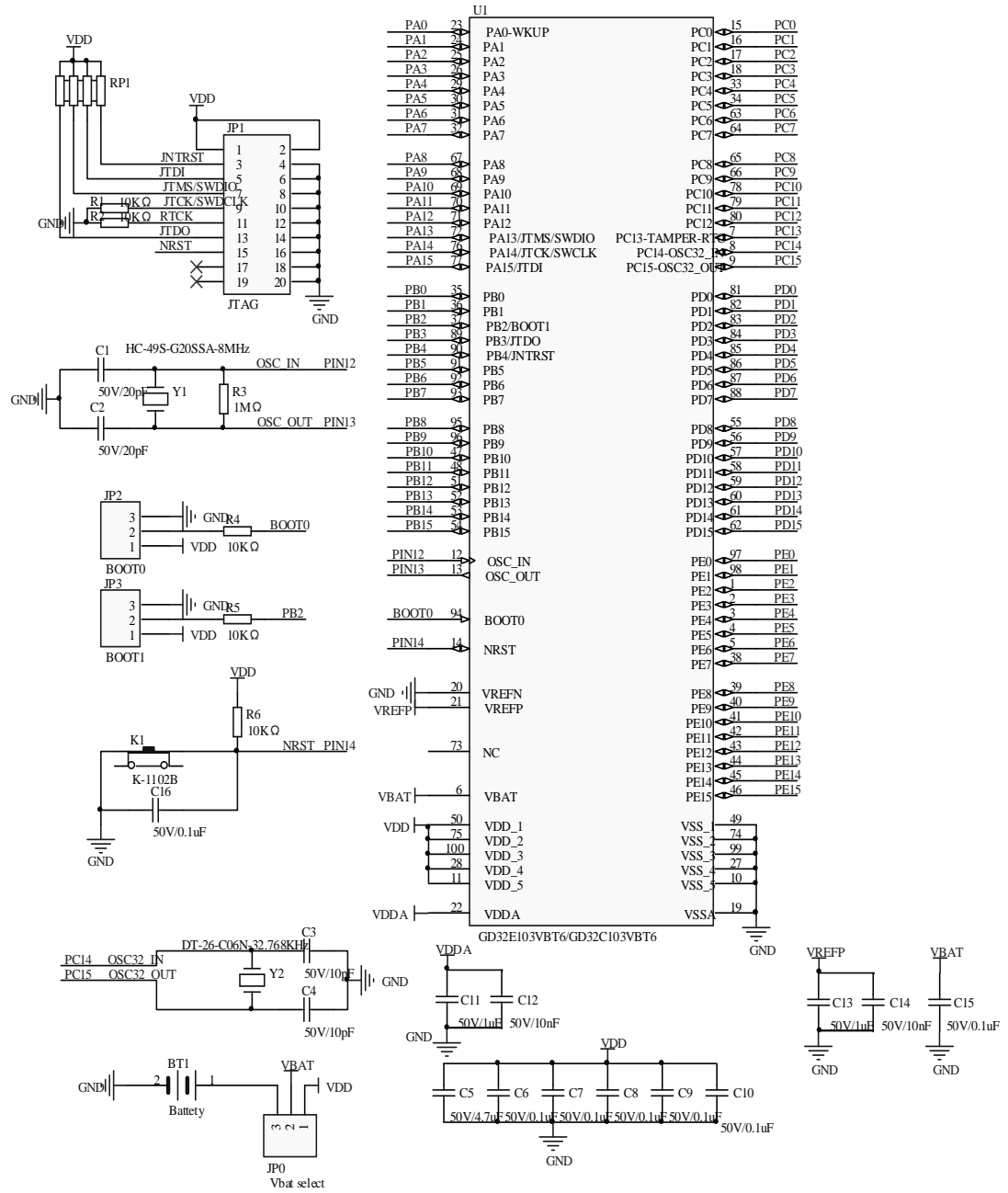


There are several ways to improve the reliability of SWD download and debugging communication and enhance the anti-interference ability of download and debugging.

1. Shorten the length of the two SWD signal lines, preferably within 15cm.
2. Weave the two SWD wires and the GND wire into a twist and twist them together.
3. Connect separately tens of pF small capacitors in parallel between the two signal lines of the SWD and the ground.
4. Any IO of the two signal lines of SWD is connected in series with a 100Ω~1kΩ resistor.

2.7. Reference Schematic Design

Figure 2-22. GD32E103/GD32C103 Recommend Reference Schematic Design



3. PCB Layout Design

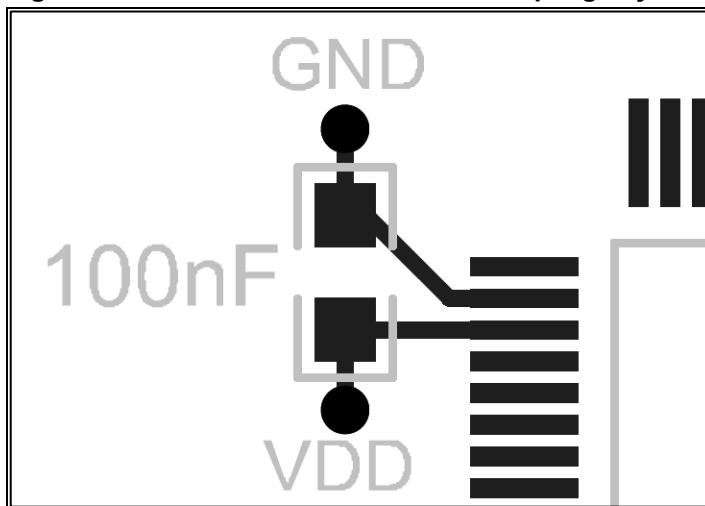
In order to enhance the functional stability and EMC performance of the MCU, it is not only necessary to consider the performance of the supporting peripheral components, but also the PCB Layout. In addition, when conditions permit, try to choose a PCB design scheme with an independent GND layer and an independent power supply layer, which can provide better EMC performance. If conditions do not allow, independent GND layer and power supply layer cannot be provided, then it is also necessary to ensure a good power supply and grounding design, such as making the GND plane under the MCU as complete as possible. For packages with EPAD, it is recommended that EPAD be grounded on the PCB Layout.

In applications with high power or strong interference, it is necessary to consider keeping the MCU away from these strong interference sources.

3.1. Power Supply Decoupling Capacitors

The GD32E103/GD32C103 series power supply has three power supply pins: V_{DD} , V_{DDA} and V_{BAT} . The 100nF decoupling capacitor can be made of ceramic, and it is necessary to ensure that the position is as close to the power supply pin as possible. The power trace should try to make it pass through the capacitor first and then reach the MCU power pin, It is recommended to punch holes near the capacitor pad to connect with GND.

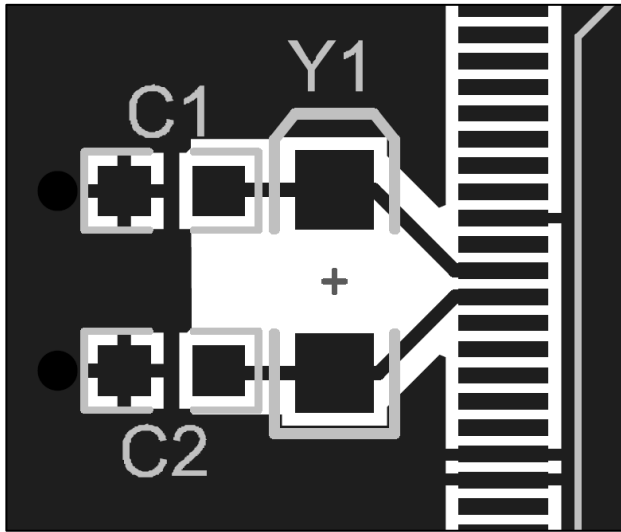
Figure 3-1. Recommend Power Pin Decoupling Layout Design



3.2. Clock Circuit

GD32E103/GD32C103 series clocks have HXTAL and LXTAL, and the clock circuit (including crystal or crystal oscillator and capacitor, etc.) is required to be placed close to the MCU clock pin, and the clock trace should be wrapped by GND as much as possible.

Figure 3-2. Recommend Clock Pin Layout Design (passive crystal)



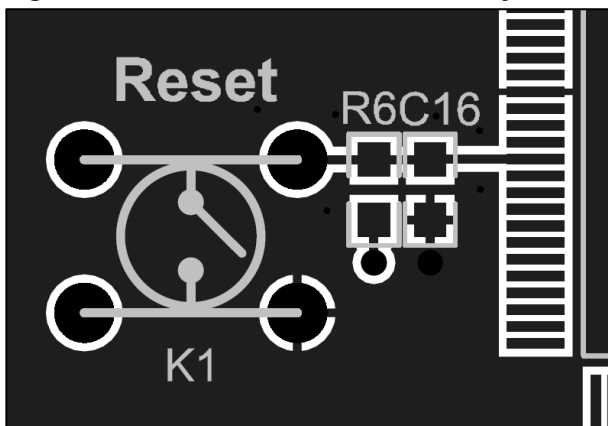
Note:

1. The crystal should be as close to the MCU clock pin as possible, and the matching capacitor should be as close as possible to the crystal.
2. The whole circuit should be on the same layer as the MCU, and the wiring should not go through the layer as much as possible.
3. The PCB area of the clock circuit should be kept as empty as possible, and no traces unrelated to the clock should be taken.
4. High-power, high-interference risk devices and high-speed wiring should be kept away from the clock crystal circuit as far as possible.
5. The clock line is grounded to achieve a shielding effect.
6. The GND of the matching capacitor should be close to the GND of the chip.

3.3. Reset Circuit

NRST trace PCB Layout reference is as follows:

Figure 3-3. Recommend NRST Trace Layout Design



Note: The resistance and capacitance of the reset circuit should be as close as possible to the NRST pin of the MCU, and the NRST trace should be kept away from devices with strong

interference risk and high-speed traces as far as possible. If conditions permit, it had better to wrap the NRST traces for better shielding effect.

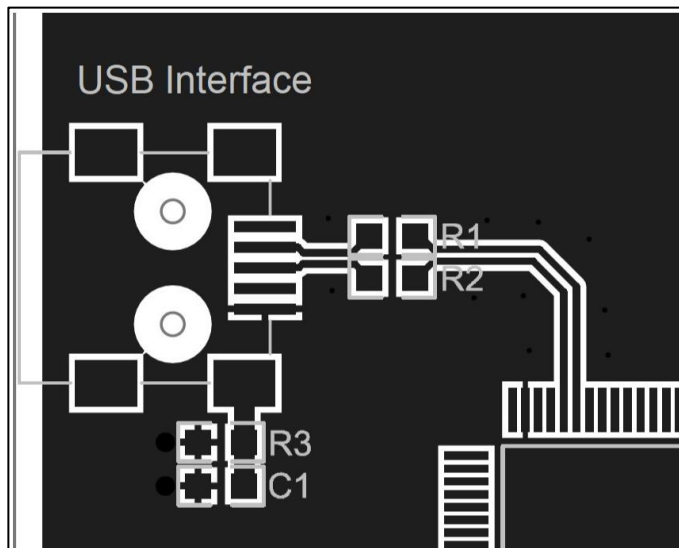
3.4. USB Circuit

The USB module has two differential signal lines, DM and DP. It is recommended that the PCB traces require a characteristic impedance of 90Ω . The differential traces should be run in strict accordance with the rule of equal length and equal distance, and the traces should be kept as short as possible. If the two differential lines are not equal in length, the short line can be compensated with a serpentine line at the terminal.

Due to impedance matching considerations, the series matching resistance is recommended to be about 50Ω . When the USB terminal interface is far away from the MCU, the series resistance value needs to be appropriately increased.

The USB differential trace reference is as follows:

Figure 3-4. Recommend USB Differential Trace Layout Design



Recommendation: $R1 = R2 = 50\Omega$, $R3 = 1M\Omega$, $C = 4700pF$.

Note:

1. Reasonable placement during layout to shorten the differential trace distance.
2. Draw differential lines first, try not to exceed two pairs of vias for a pair of differential lines, and place them symmetrically.
3. Symmetrical parallel wiring to ensure that the two lines are tightly coupled, avoiding 90° , arc or 45° wiring.
4. Devices such as resistance-capacitor, EMC connected to the differential traces, or test points should also be symmetrical.

4. Package Description

The GD32E103/GD32C103 series has a total of 4 package types, namely LQFP100, LQFP64, LQFP48, and QFN36.

Table 4-1. Package Description

Ordering code	Package
GD32C103TxU6/GD32E103TxU6	QFN36(6x6, 0.5 pitch)
GD32C103CxT6/GD32E103CxT6	LQFP48(7x7, 0.5 pitch)
GD32C103RxT6/GD32E103RxT6	LQFP64(10x10, 0.5 pitch)
GD32C103VxT6/GD32E103VxT6	LQFP100(14x14, 0.5 pitch)

(Original dimensions are in millimeters)

5. Revision history

Table 5-1. Revision history

Revision No.	Description	Date
1.0	Initial Release	Jun.13, 2022
1.1	Update section 2.1.3 to provide all packaging power supply design drawings, explaining the connection of relevant pins within the chip.	Jun.21, 2023
1.2	Update section 2.1.3 , Update NRST related content.	Apr.28, 2024
1.3	Refine the content related to power supply detection and reset, and add Section 2.2.	Dec.15, 2024

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